# **FET Switch**

# 100 V, 800 m $\Omega$ , N-Channel, TSOP-6

The NUD3048 provides a single device solution for a number of applications requiring a low power, high voltage, FET switch. The package includes a gate resistor and gate to source zener clamp. This switch can accommodate a wide range of input voltages, making it compatible with most current logic levels. Its 100 V rating makes it compatible with 48 V telecom applications.

#### **Features**

- 100 V Rating On Gate 2
- Integrated 100 k Rg Option
- Integrated ESD Diode Protection
- Low Threshold Voltage

### **Typical Applications**

- FET Switch
- Inverter
- Level Shifter
- Inrush Limiter
- Relay Driver

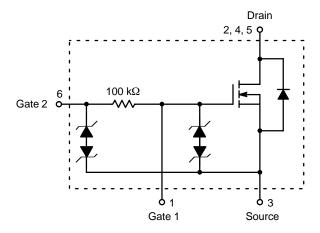


Figure 1. Block Diagram



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MARKING DIAGRAM



TSOP-6 CASE 318G STYLE 9



JW7 = Specific Device Code
D = Date Code

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NUD3048MT1	TSOP-6	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### **MAXIMUM RATINGS**

Symbol	Rating	Value	Unit
V <sub>DSS</sub>	Drain to Source Voltage – Continuous	100	V
V <sub>G1SS</sub>	Gate to Source Voltage – Continuous @ 1.0 mA	15	V
I <sub>D</sub>	Drain Current – Continuous (T <sub>A</sub> =25°C) (Note 1) (Note 2)	0.7 1.2	Α
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> =25°C) (Note 1) (Note 2)	0.66 1.56	W
V <sub>G2SS</sub>	Gate Resistor to Source Voltage – Continuous	100	V
T <sub>Jmax</sub>	Maximum Junction Temperature	150	°C
$R_{ hetaJA}$	Thermal Impedance (Junction-to-Ambient) (Note 1) Thermal Impedance (Junction-to-Ambient) (Note 2)	190 80	°C/W
ESD	Human Body Model (HBM) Class 2 Machine Model Class A According to EIA/JESD22/A114 Specification	2000 100	V V

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> =25°C unless otherwise noted.)

Characteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS	<u>.</u>				
Drain to Source Leakage Current (V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V)	I <sub>DSS</sub>	-	20	100	μΑ
Gate Body Leakage Current ( $V_{GS} = 10 \text{ V}$ , $V_{DS} = 0 \text{ V}$ ) ( $V_{GS} = 10 \text{ V}$ , $V_{DS} = 0 \text{ V}$ , $V_{J} = 125^{\circ}\text{C}$ )	I <sub>GSS</sub> I <sub>GSS</sub>	- -	3.0 6.0	10 20	μΑ
ON CHARACTERISTICS	•		•	•	•
Gate Threshold Voltage (I <sub>D</sub> = 1.0 mA)	V <sub>GS</sub>	1.3	1.7	2.0	V
Drain to Source Resistance ( $V_{GS} = 4.5 \text{ V}$ , $I_D = 100 \text{ mA}$ )	R <sub>DS(on)</sub>	_	0.65	0.82	Ω
Drain to Source Resistance (V <sub>GS</sub> = 10 V, I <sub>D</sub> = 100 mA)	R <sub>DS(on)</sub>	-	0.6	0.72	Ω
DYNAMIC CHARACTERISTICS	•		•	•	•
Input Capacitance ( $V_{DS} = 5.0 \text{ V}, V_{GS} = 0 \text{ V}, f = 10 \text{ kHz}$ )	C <sub>iss</sub>	-	135	-	pF
Output Capacitance ( $V_{DS} = 5.0 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $f = 10 \text{ kHz}$ )	C <sub>oss</sub>	_	75	-	pF
Transfer Capacitance ( $V_{DS} = 5.0 \text{ V}, V_{GS} = 0 \text{ V}, f = 10 \text{ kHz}$ )	C <sub>rss</sub>	_	26	-	pF
GATE BIAS CHARACTERISTICS					
Gate Resistor	R <sub>G</sub>	75	100	125	kΩ
Gate Zener Breakdown Voltage (I <sub>Z</sub> = 1.0 mA) (Note 3) Gate Zener Breakdown Voltage (I <sub>Z</sub> = 3.0 mA) (Note 4)	Vz	15 100	17 115	- -	V

- 1. Min pad, 1 oz. Cu.

- 1 inch pad, 1 oz Cu.
   Measured from gate 1 to source.
   Measured from gate 2 to source.

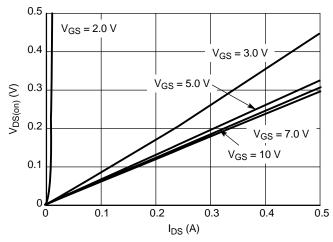


Figure 2.  $\rm V_{DS(on)}$  Variation with  $\rm I_{DS}$  and  $\rm$  Gate Voltage

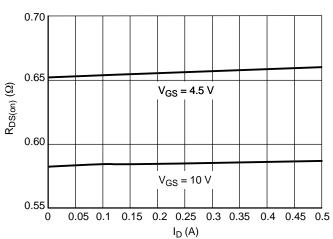


Figure 3. On Resistance Variation with Drain Current and Gate Voltage

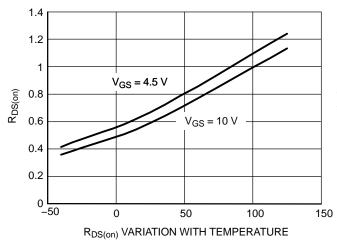


Figure 4. Variation of  $R_{DS(on)}$  with Temperature and Gate Voltage at  $I_D$  = 100 mA

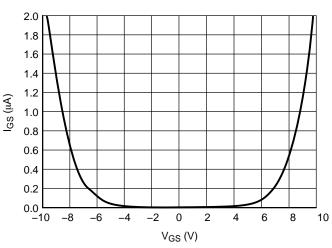


Figure 5. Gate Leakage Current Variation with Gate Voltage

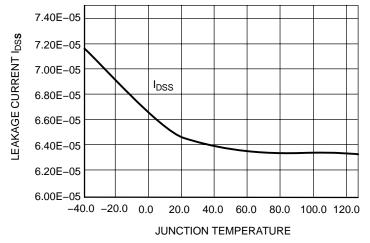
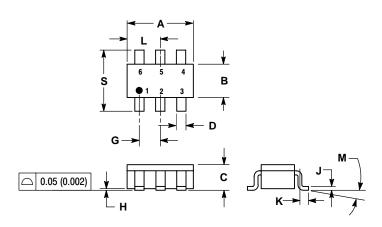


Figure 6. Variation of Leakage Current  $I_{DSS}$  (A) with  $V_{GS} = 0$  V and  $V_{DS} = 100$  V

### PACKAGE DIMENSIONS

### TSOP-6 CASE 318G-02 **ISSUE L**



#### NOTES:

- DIMENSIONING AND TOLERANCING PER
   ANSI Y14.5M. 1982.
- CONTROLLING DIMENSION: MILLIMETER.
  MAXIMUM LEAD THICKNESS INCLUDES
  LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS
- OF BASE MATERIAL.
  DIMENSIONS A AND B DO NOT INCLUDE
  MOLD FLASH, PROTRUSIONS, OR GATE BURRS

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.90	3.10	0.1142	0.1220	
В	1.30	1.70	0.0512	0.0669	
С	0.90	1.10	0.0354	0.0433	
D	0.25	0.50	0.0098	0.0197	
G	0.85	1.05	0.0335	0.0413	
Н	0.013	0.100	0.0005	0.0040	
J	0.10	0.26	0.0040	0.0102	
K	0.20	0.60	0.0079	0.0236	
L	1.25	1.55	0.0493	0.0610	
M	0 °	10°	0 °	10°	
S	2.50	3.00	0.0985	0.1181	

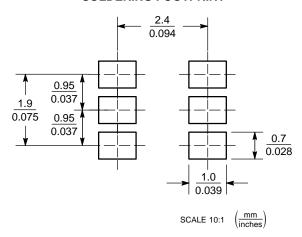
## STYLE 9:

PIN 1. LOW VOLTAGE GATE 2. DRAIN

- 3. SOURCE 4. DRAIN

- 5. DRAIN 6. HIGH VOLTAGE GATE

### **SOLDERING FOOTPRINT**



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